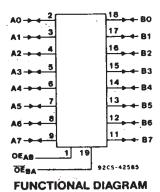


Data sheet acquired from Harris Semiconductor SCHS286



# Octal-Bus Transceiver, 3-State, Non-Inverting

#### **Type Features:**

- Buffered inputs
- Typical propagation delay: 4.5 ns @ V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C, C<sub>L</sub> = 50 pF

The RCA CD54/74AC623 and CD54/74ACT623 octal-bus transceivers use the RCA ADVANCED CMOS technology. They are non-inverting, 3-state, bidirectional transceiver-buffers that allow for two-way transmission from "A" bus to "B" bus or "B" bus to "A" bus, depending on the logic levels of the Output Enable ( $\overline{OE}_{BB}$ ,  $\overline{OE}_{BA}$ ) inputs.

The dual Output Enable provision gives these devices the capability to store data by simultaneously enabling OEAB and OEBA. Each output reinforces its input under these conditions, and when all other data sources to the bus lines are at high-impedance, both sets of bus lines will remain in their last states.

The CD74AC623 and CD74ACT623 are supplied in 20-lead dual-in-line plastic packages (E suffix) and in 20-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Commercial (0 to 70°C); Industrial (-40 to +85°C); and Extended Industrial/Military (-55 to +125°C).

The CD54AC623 and CD54ACT623, available in chip form (H suffix), are operable over the -55 to +125°C temperature range.

## Family Features:

- Exceeds 2-kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-resistant CMOS process and circuit design
- Speed of bipolar FAST\*/AS/S with significantly reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply
- ± 24-mA output drive current
  - Fanout to 15 FAST\* ICs
  - Drives 50-ohm transmission lines

#### **TRUTH TABLE**

OUTPUT EN	ABLE INPUTS	OPERATION
OEBA	OE <sub>AB</sub>	OPERATION
L	L	B DATA TO A BUS
Н	н	A DATA TO B BUS
Н	L	ISOLATION
L	н.	B DATA TO A BUS, A DATA TO B BUS

H = High level, L = Low level

Note: To prevent excess currents in the High-Z (isolation) modes, all I/O terminals should be terminated with 10 k $\Omega$  to 1 M $\Omega$  resistors.

This data sheet is applicable to the CD74AC623 and CD54/74ACT623. The CD54AC623 was not acquired from Harris Semiconductor.

<sup>\*</sup>FAST is a Registered Trademark of Fairchild Semiconductor Corp.

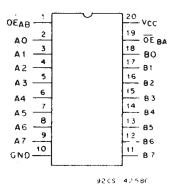
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## **RECOMMENDED OPERATING CONDITIONS:**

For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIA	LIMITS		
	MIN.	MAX.	UNITS	
Supply-Voltage Range, V <sub>CC</sub> *:  (For T <sub>A</sub> = Full Package-Temperature Range)  AC Types  ACT Types	1.5 4.5	5.5 5.5	V	
DC Input or Output Voltage, V <sub>i</sub> , V <sub>o</sub>	0	Vcc	V	
Operating Temperature, T <sub>A</sub>	-55	+125	°C	
Input Rise and Fall Slew Rate, dt/dv at 1.5 V to 3 V (AC Types) at 3.6 V to 5.5 V (AC Types) at 4.5 V to 5.5 V (ACT Types)	0 0 0	50 20 10	ns/V ns/V ns/V	

<sup>\*</sup>Unless otherwise specified, all voltages are referenced to ground.



**TERMINAL ASSIGNMENT** 

Technical Data

# CD54/74AC623 CD54/74ACT623

STATIC ELECTRICAL CHARACTERISTICS: AC Series

				AMBIENT TEMPERATURE (TA) - °C						>	
CHARACTERISTI	CS	TEST CO	NDITIONS	V <sub>cc</sub>	+2	25	-40 to	o +85	-55 to +125		UNITS
		V <sub>1</sub> (V)	l <sub>o</sub> (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
High-Level Input				1.5	1.2		1.2	<del></del>	1.2		
Voltage	V <sub>IH</sub>			3	2.1		2.1		2.1		V
•*				5.5	3.85		3.85	_	3.85		
Low-Level Input				1.5	_	0.3	_	0.3	_	0.3	
Voltage	VIL			3	<b>—</b>	0.9	_	0.9		0.9	V
				5.5	777	1.65	,	1.65	_	1.65	
High-Level Output			-0.05	1.5	1.4	_	1.4	_	1.4		]
Voltage	V <sub>OH</sub>	VIH	-0.05	3	2.9	_	2.9		2.9	_	]
		or	-0.05	4.5	4.4	<u> </u>	4.4	<u> </u>	4.4		]
		VIL	-4	3	2.58	<u> </u>	2.48		2.4		V
		:	-24	4.5	3.94	_	3.8	h — i	3.7		]
		1	-75	5.5		_	3.85	_	_	<u> </u>	]
		#, * {	-50	5.5	<u> </u>	_			3.85	_	
Low-Level Output	· · · · · ·		0.05	1.5	_	0.1	_	0.1		0.1	
Voltage	Vol	V <sub>IH</sub>	0.05	3	_	0.1	_	0.1	_	0.1	
		or	0.05	4.5		0.1	_	0:1		0.1	]
		ViL	12	3	_	0.36	_	0.44	_	0.5	] v
			24	4.5	_	0.36	_	0.44	_	0.5	] -
		1	75	5.5	_	_		1.65	_		
		#, * {	50	5.5		_	_	_		1.65	7
Input Leakage Current	1	V <sub>cc</sub> or GND		5.5		±0.1		±1		±1	μΑ
3-State Leakage Current	loz	V <sub>IH</sub> or V <sub>IL</sub> V <sub>O</sub> = V <sub>∞</sub> or GND		5.5		±0.5		±5	_	±10	μΑ
Quiescent Supply Current, MSI	Icc	V <sub>cc</sub> or GND	0	5.5	_	8	_	80	_	160	μΑ

<sup>#</sup>Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize nower dissipation

power dissipation.

\* Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

## STATIC ELECTRICAL CHARACTERISTICS: ACT Series

						AMBIENT TEMPERATURE (TA) - °C					
CHARACTERISTICS		TEST CONDITIONS		V <sub>cc</sub> (V)	+	+25		-40 to +85		-55 to +125	
		V, (V)	l <sub>o</sub> (mA)	(v)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	UNITS
High-Level Input Voltage	V <sub>IH</sub>			4.5 to 5.5	2	_	2		2	_	·V
Low-Level Input Voltage	V <sub>IL</sub>			4.5 to 5.5	_	0.8	_	0.8	_	0.8	V,
High-Level Output		V <sub>IH</sub>	-0.05	4.5	4.4	_	4.4		4.4		
Voltage	V <sub>OH</sub>	or	-24	4.5	3.94	·	3.8	<u> </u>	3.7	: _	
		V <sub>IL</sub>	-75	5.5		_	3.85	_	_	T -	<b>'</b>
		#, * {	-50	5.5		_	_		3.85	_	<b>.</b>
Low-Level Output		V <sub>IH</sub>	0.05	4.5	_	0.1	_	0.1	_	0.1	
Voltage	Voltage Vol.	or	24	4.5		0.36		0.44	-	0.5	1 v
		٧١. (	75	5.5		_	_	1.65		_	1
		#, * {	50	5.5		_	_		_	1.65	1
Input Leakage Current	I,	V <sub>∞</sub> or GND		5.5		±0.1		±1	_	±1	μΑ
3-State Leakage Current	loz	V <sub>IH</sub> or V <sub>IL</sub> Vo = Vcc or GND		5.5	_	±0.5	_	±5	· . <del></del>	±10	μΑ
Quiescent Supply Current, MSI	lœ	V <sub>cc</sub> or GND	0	5.5	_	8	<b>-</b> .	80	_	160	μΑ
Additional Quiescent St Current per Input Pin TTL Inputs High 1 Unit Load	Δl <sub>∞</sub>	V∞-2.1		4.5 to 5.5		2.4		2.8	_	3	mA

#Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.
\*Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

## **ACT INPUT LOADING TABLE**

INPUT	UNIT LOAD*
An, Bn	0.83
OE <sub>BA</sub>	0.64
OE <sub>AB</sub>	0.15

\*Unit load is  $\Delta l_{\rm CC}$  limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25° C.

# CD54/74AC623 CD54/74ACT623

SWITCHING CHARACTERISTICS: AC Series; t,, t, = 3 ns, C, = 50 pF

	•		AMBI	ENT TEMPE	RATURE (T	A) - °C	╛
CHARACTERISTICS	SYMBOL	(V)	-40 t	o +85	-55 to +125		UNITS
			MIN.	MAX.	MIN.	MAX.	
Propagation Delays: Data to Output	tpux tpuL	1.5 3.3* 5†	3.5 2.5	108 12.2 8.7	3.4 2.4	120 13.4 9.6	ns
Output Disable to Output	telz tenz	1.5 3.3 5	 4.8 3.5	153 17.1 12.2	4.7 3.4	168 18.8 13.4	ns
Output Enable to Output	t <sub>PZL</sub> t <sub>PZH</sub>	1.5 3.3 5	 4.8 3.5	153 17.1 12.2	4.7 3.4	168 18.8 13.4	ns
Power Dissipation Capacitance	C <sub>PD</sub> §	_	66	Тур.	66	Тур.	pF
Min. (Valley) V <sub>OH</sub> During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>онv</sub> See Fig. 1	5	4 Typ. @ 25°C				V
Max. (Peak) V <sub>OL</sub> During Switching of Other Outputs (Output Under Test Not Switching)	Volp See Fig. 1	5	1 Typ. @ 25°C				V
Input Capacitance	Cı	_		10		10	pF
3-State Output Capacitance	Co		T -	15	_	15	pF

## SWITCHING CHARACTERISTICS: ACT Series; t,, t, = 3 ns, C, = 50 pF

			AMBI				
CHARACTERISTICS	SYMBOL	V <sub>cc</sub> (V)		o +85	-55 to	UNITS	
Ji mino i Ellio i i o			MIN.	MAX.	MIN.	MAX.	
Propagation Delays: Data to Output	tрін трні	5†	2.7	9.6	2.7	10.6	ns
Output Disable to Output	telz tenz	5	3.7	13.1	3.6	14.4	ns
Output Enable to Output	t <sub>PZH</sub> t <sub>PZL</sub>	5	3.7	13.1	3.6	14.4	ns
Power Dissipation Capacitance	C <sub>PD</sub> §	-	66	Тур.	66 Typ.		pF
Min. (Valley) V <sub>OH</sub> During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>онv</sub> See Fig. 1	5	4 Typ. @ 25°C				V
Max. (Peak) Vol. During Switching of Other Outputs (Output Under Test Not Switching)	V <sub>OLP</sub> See Fig. 1	5	1 Typ. @ 25°C				٧
Input Capacitance	Cı			10		10	pF
3-State Output Capacitance	Co			15	_	15	pF

\*3.3 V: min. is @ 3.6 V max. is @ 3 V

†5 V: min. is @ 5.5 V max. is @ 4.5 V

§C<sub>PD</sub> is used to determine the dynamic power consumption, per channel.

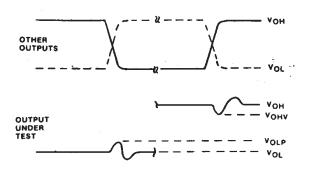
For AC series:  $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$ For ACT series:  $P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC} \Delta I_{CC}$  where  $f_i = \text{input frequency}$ 

 $C_L$  = output load capacitance

 $V_{CC}$  = supply voltage.

# CD54/74AC623 CD54/74ACT623

### PARAMETER MEASUREMENT INFORMATION



#### NOTES:

- 1. VOHY AND VOLP ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST.
- 2. INPUT PULSES HAVE THE FOLLOWING CHARACTERISTICS:
- PRR ≤ 1 MHz, I<sub>7</sub> = 3 ns, I<sub>7</sub> = 3 ns, SKEW 1 ns.

  3. R.F. FIXTURE WITH 700-MHz DESIGN RULES REQUIRED.
  IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED
  WITH 0.1 <sub>A</sub>F CAPACITOR. SCOPE AND PROBES REQUIRE
  700-MHz BANDWIDTH.

9205-4240€

Fig. 1 - Simultaneous switching transient waveforms.

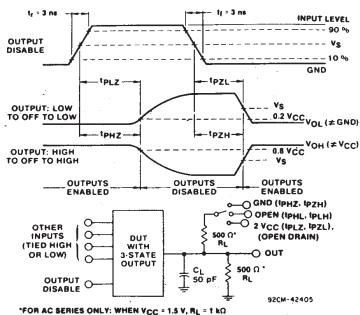
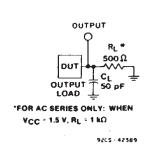


Fig. 2 - Three-state propagation delay times and test circuit.



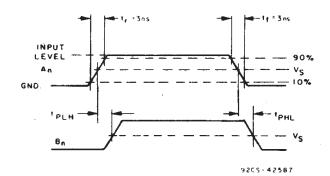


Fig. 3 - Propagation delay times and test circuit.

	CD54/74AC	CD54/74ACT
Input Level	Vcc	3 V
Input Switching Voltage, Vs	0.5 V <sub>cc</sub>	1.5 V
Output Switching Voltage, Vs	0.5 V <sub>cc</sub>	0.5 V <sub>CC</sub>

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